

Dear Colleagues,

The 7th International Beam Instrumentation Conference (IBIC 2018) was held in Shanghai (China) between September 9th and 13th 2018. It was held by Shanghai institute of applied physics (SINAP), which is the photon science center of China, operating two large scale facilities: SSRF and SXFEL. Like its predecessors, this conference is also dedicated to exploring the physics and engineering challenges of beam diagnostics and measurement techniques for charged particle beams.

Shanghai, located on China's central eastern coast at the mouth of the Yangtze River, is mainland China's center for commerce and finance. The city is also an emerging tourist destination renowned for its historical landmarks such as the Bund, Xintiandi, Yu Garden and the Oriental Pearl Tower. In addition, Shanghai is one of the leading technological centers of China, and a visit to the SSRF and SXFEL was organized.

The 3.5 day programme of the 2018 IBIC conference included 15 invited and 23 contributed talks, and 1 public lecture. Furthermore, 149 posters were presented in the 3 poster sessions, and a 3 day long vendor exhibition with 19 exhibitors could be visited during the conference. In total, 234 participants coming from 18 countries gather around during the 3.5 days of the conference. To all of them, the Organizing Committee is pleased to thank them for their enthusiastic participation.

Not only to the participants, we would like to explicitly express our gratitude to all those who have contributed to this conference: the Scientific Committee for forming a balanced and interesting programme, the Editorial Team for working hard to enable us to present these proceedings, and last but not least, the Local Organization Committee for turning this conference into reality.

Zhentang Zhao
IBIC 2018 conference chair

Yongbin Leng
IBIC 2018 Co-chair and PC chair